MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data speet





APPLICATION

- Load Switch for Portable Devices

FEATURE

★ TrenchFET Power MOSFET

V _{(BR)DSS}	R _{DS(on)} MAX	l _D
-20 V	90 mΩ@-4.5V	
	110 mΩ@-2.5V	-3 A





1. GATE

B. DRAIN

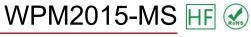
SOT-23-3L

Maximum ratings (Ta=25℃ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage		-20	V
Gate-Source Voltage	V_{GS}	±8	V
Continuous Drain Current	I _D	-3	
Pulsed Drain Current	I _{DM}	-10	Α
Continuous Source-Drain Diode Current	Is	-0.72	
Maximum Power Dissipation	P _D	0.4	W
Thermal Resistance from Junction to Ambient(t ≤5s)	R _{θJA}	312.5	°C/W
Junction Temperature	TJ	150	
Storage Temperature	T _{stg}	-55 ~+150	℃

$\rm T_a = 25 \ ^{\circ}\!\! C$ unless otherwise specified

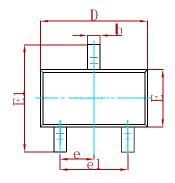
Parameter	Symbol	Test Condition	Min	Тур	Max	Units
Static				•		
Drain-source breakdown voltage	V(BR)DSS	V _G S = 0V, I _D =-250μA	-20			V
Gate-source threshold voltage	VGS(th)	V _{DS} =V _{GS} , I _D =-250μA	-0.4		-1	V
Gate-source leakage	I _{GSS}	V _{DS} =0V, V _{GS} =±8V			±100	nA
Zero gate voltage drain current	I _{DSS}	V _{DS} =-20V, V _{GS} =0V			-1	μA
		V _{GS} =-4.5V, I _D =-2.8A		0.080	0.90	Ω
Drain-source on-state resistance ^a	RDS(on)	V _{GS} =-2.5V, I _D =-2.0A		0.90	0.110	
Forward transconductance ^a	g _{fs}	V _{DS} =-5V, I _D =-2.8A		6.5		S
Dynamic ^b						
Input capacitance	C _{iss}			405		pF
Output capacitance	Coss	V _{DS} =-10V,V _{GS} =0V,f =1MHz		75		
Reverse transfer capacitance	C _{rss}			55		
Total sate above	0	Q _g V _{DS} =-10V,V _{GS} =-4.5V,I _D =-3A		5.5	10	
Total gate charge	Цg			3.3	6	
Gate-source charge	Q _{gs}	V _{DS} =-10V,V _{GS} =-2.5V,I _D =-3A		0.7		nC
Gate-drain charge	Q_{gd}			1.3		
Gate resistance	Rg	f=1MHz		6.0		Ω
Turn-on delay time	td(on)	.,		11	20	
Rise time	t r	V _{DD} =-10V,		35	60	
Turn-off delay time	td(off)	$R_L=10\Omega$, $I_D=-1A$, $V_{GEN}=-4.5V$, $R_G=1\Omega$		30	50	ns -
Fall time	tf	V _{GEN} =-4.5V,Ry=112		10	20	
Drain-source body diode characterist	tics	ı	1	1	1	1
Continuous source-drain diode current	Is	Tc=25℃			-1.3	А
Pulse diode forward current ^a	I _{SM}				-10	
Body diode voltage	V _{SD}	I _S =-0.7A		-0.8	-1.2	V

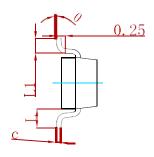


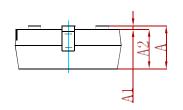




PACKAGE MECHANICAL DATA

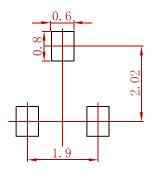






Comple al	Dimensions	s In Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.037 TYP		
e1	1.800	2.000	0.071	0.079	
Ĺ	0.550 REF		0.02	2 REF	
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
WPM2015-MS	SOT-23-3	3000



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